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12 LVDS/24 CMOS Output Clock Generator

Data Sheet

AD9522-5

FEATURES

- Low phase noise, phase-locked loop (PLL)
  - Supports external 3.3 V/5 V voltage controlled oscillator (VCO)/VCXO to 2.4 GHz
  - 1 differential or 2 single-ended reference inputs
  - Accepts CMOS, LVPECL, or LVDS references to 250 MHz
  - Accepts 16.62 MHz to 33.3 MHz crystal for reference input
  - Optional reference clock doubler
  - Reference monitoring capability
  - Revertive automatic and manual reference switchover/holdover modes
  - Glitch-free switchover between references
  - Automatic recovery from holdover
  - Digital or analog lock detect, selectable
  - Optional zero delay operation
- Twelve 800 MHz LVDS outputs divided into 4 groups
  - Each group of 3 has a 1-to-32 divider with phase delay
  - Additive output jitter as low as 242 fs rms
  - Channel-to-channel skew grouped outputs < 60 ps
  - Each LVDS output can be configured as 2 CMOS outputs (for $f_{OUT} \leq 250$ MHz)
- Automatic synchronization of all outputs on power-up
- Manual synchronization of outputs as needed
- SPI- and I²C-compatible serial control port
- 64-lead LFCSP
- Nonvolatile EEPROM stores configuration settings

APPLICATIONS

- Low jitter, low phase noise clock distribution
- Clock generation and translation for SONET, 10Ge, 10G FC, and other 10 Gbps protocols
- Forward error correction (G.710)
- Clocking high speed ADCs, DACs, DDSs, DDCs, DUCs, MxFEs
- High performance wireless transceivers
- ATE and high performance instrumentation
- Broadband infrastructures

GENERAL DESCRIPTION

The AD9522-5[1] provides a multioutput clock distribution function with subpicosecond jitter performance, along with an on-chip PLL that can be used with an external VCO.

FUNCTIONAL BLOCK DIAGRAM

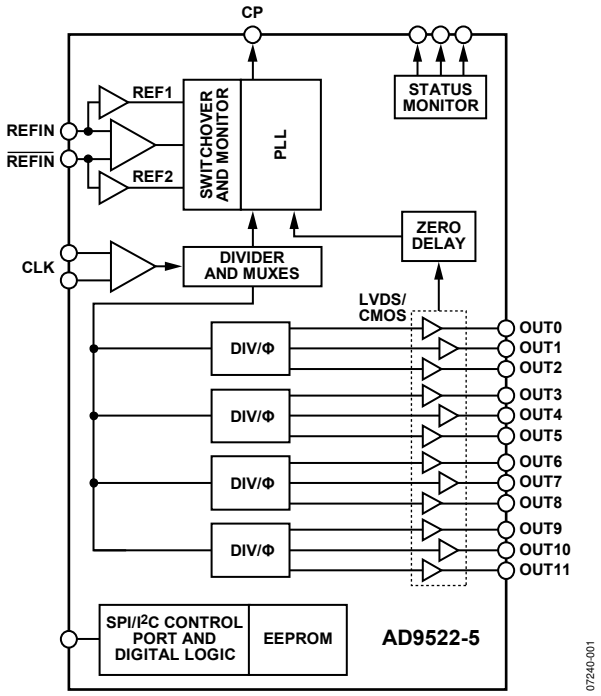

Figure 1.

The AD9522 serial interface supports both SPI and I²C® ports. An in-package EEPROM can be programmed through the serial interface and store user-defined register settings for power-up and chip reset.

The AD9522 features 12 LVDS outputs in four groups. Any of the 800 MHz LVDS outputs can be reconfigured as two 250 MHz CMOS outputs.

Each group of outputs has a divider that allows both the divide ratio (from 1 to 32) and the phase (coarse delay) to be set.

The AD9522 is available in a 64-lead LFCSP and can be operated from a single 3.3 V supply. The external VCO can have an operating voltage up to 5.5 V.

The AD9522 is specified for operation over the standard industrial range of −40°C to +85°C.

The AD9520-5 is an equivalent part to the AD9522-5 featuring LVPECL/CMOS drivers instead of LVDS/CMOS drivers.

[1] The AD9522 is used throughout this data sheet to refer to all the members of the AD9522 family. However, when AD9522-5 is used, it is referring to that specific member of the AD9522 family.

Rev. A

Document Feedback

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- AD9522-5 Evaluation Board

DOCUMENTATION

Application Notes

- AN-0983: Introduction to Zero-Delay Clock Timing Techniques

Data Sheet

- AD9522-5: 12 LVDS/24 CMOS Output Clock Generator Data Sheet

User Guides

- Evaluation Software Documentation

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- Evaluation Software Tools

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- ADIsimCLK Design and Evaluation Software
- AD9522-x IBIS Models

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Product Selection Guide

- RF Source Booklet

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- AD9522-5 Material Declaration
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TABLE OF CONTENTS

REVISION HISTORY

3/15—Rev. 0 to Rev. A

12/08—Revision 0: Initial Version

SPECIFICATIONS

Typical (typ) is given for VS = 3.3 V ± 5%; VS ≤ VCP ≤ 5.25 V; T_A = 25°C; RSET = 4.12 kΩ; CPRSET = 5.1 kΩ, unless otherwise noted. Minimum (min) and maximum (max) values are given over full VS and T_A (−40°C to +85°C) variation.

POWER SUPPLY REQUIREMENTS

Table 1.

Parameter	Min	Typ	Max	Unit	Test Conditions/Comments
VS	3.135	3.3	3.465	V	3.3 V ± 5%
VCP	VS		5.25	V	This supply is usually at the same voltage as VS; set VCP = 5.0 V ± 5% only if connecting a 5 V external VCO/VCXO
RSET Pin Resistor		4.12		kΩ	Sets internal biasing currents; connect to ground
CPRSET Pin Resistor		5.1		kΩ	Sets internal CP current range, nominally 4.8 mA (CP_Isb = 600 µA); actual current can be calculated by CP_Isb = 3.06/CPRSET; connect to ground

PLL CHARACTERISTICS

Table 2.

Parameter	Min	Typ	Max	Unit	Test Conditions/Comments
REFERENCE INPUTS					
Differential Mode (REFIN, $\overline{\text{REFIN}}$)					Differential mode (can accommodate single-ended input by ac grounding the unused complementary input)
Input Frequency	0		250	MHz	Frequencies below about 1 MHz must be dc-coupled; be careful to match V_{CM} (self-bias voltage)
Input Sensitivity		280		mV p-p	PLL figure of merit (FOM) increases with increasing slew rate (see Figure 11); the input sensitivity is sufficient for ac-coupled LVDS and LVPECL signals
Self-Bias Voltage, REFIN	1.35	1.60	1.75	V	Self-bias voltage of REFIN[1]
Self-Bias Voltage, $\overline{\text{REFIN}}$	1.30	1.50	1.60	V	Self-bias voltage of $\overline{\text{REFIN}}$[1]
Input Resistance, REFIN	4.0	4.8	5.9	kΩ	Self-biased[1]
Input Resistance, $\overline{\text{REFIN}}$	4.4	5.3	6.4	kΩ	Self-biased[1]
Dual Single-Ended Mode (REF1, REF2)					Two single-ended CMOS-compatible inputs
Input Frequency (AC-Coupled with DC Offset Off)	10		250	MHz	Slew rate must be > 50 V/µs
Input Frequency (AC-Coupled with DC Offset On)			250	MHz	Slew rate must be > 50 V/µs, and input amplitude sensitivity specification must be met; see input sensitivity
Input Frequency (DC-Coupled)	0		250	MHz	Slew rate > 50 V/µs; CMOS levels
Input Sensitivity (AC-Coupled with DC Offset Off)	0.55		3.28	V p-p	VIH must not exceed VS
Input Sensitivity (AC-Coupled with DC Offset On)	1.5		2.78	V p-p	VIH must not exceed VS
Input Logic High, DC Offset Off	2.0			V	
Input Logic Low, DC Offset Off			0.8	V	
Input Current	−100		+100	µA	
Input Capacitance		2		pF	Each pin, REFIN (REF1)/$\overline{\text{REFIN}}$ (REF2)
Pulse Width High/Low	1.8			ns	Amount of time a square wave is high/low determines the allowable input duty cycle
Crystal Oscillator					
Crystal Resonator Frequency Range	16.62		33.33	MHz	
Maximum Crystal Motional Resistance			30	Ω	
PHASE/FREQUENCY DETECTOR (PFD)					
PFD Input Frequency			100	MHz	Antibacklash pulse width = 1.3 ns, 2.9 ns
			45	MHz	Antibacklash pulse width = 6.0 ns
Reference Input Clock Doubler Frequency	0.004		50	MHz	Antibacklash pulse width = 1.3 ns, 2.9 ns
Antibacklash Pulse Width		1.3		ns	Register 0x017[1:0] = 01b
		2.9		ns	Register 0x017[1:0] = 00b; Register 0x017[1:0] = 11b
		6.0		ns	Register 0x017[1:0] = 10b

Parameter	Min	Typ	Max	Unit	Test Conditions/Comments
CHARGE PUMP (CP)					
I_{CP} Sink/Source					Programmable
High Value		4.8		mA	With CPRSET = 5.1 kΩ; higher I_{CP} is possible by changing CPRSET
Low Value		0.60		mA	With CPRSET = 5.1 kΩ; lower I_{CP} is possible by changing CPRSET
Absolute Accuracy		2.5		%	Charge pump voltage set to $V_{CP}/2$
CPRSET Range	2.7		10	kΩ	
I_{CP} High Impedance Mode Leakage		1		nA	
Sink-and-Source Current Matching		1		%	0.5 V < V_{CP} < VCP − 0.5 V; V_{CP} is the voltage on the CP (charge pump) pin; VCP is the voltage on the VCP power supply pin
I_{CP} vs. V_{CP}		1.5		%	0.5 V < V_{CP} < VCP − 0.5 V
I_{CP} vs. Temperature		2		%	V_{CP} = VCP/2 V
PRESCALER (PART OF N DIVIDER)					
Prescaler Input Frequency					
P = 1 FD			300	MHz	
P = 2 FD			600	MHz	
P = 3 FD			900	MHz	
P = 2 DM (2/3)			200	MHz	
P = 4 DM (4/5)			1000	MHz	
P = 8 DM (8/9)			2400	MHz	
P = 16 DM (16/17)			3000	MHz	
P = 32 DM (32/33)			3000	MHz	
Prescaler Output Frequency			300	MHz	A, B counter input frequency (prescaler input frequency divided by P)
PLL N DIVIDER DELAY					Register 0x019[2:0]; see Table 47
000		Off			
001		385		ps	
010		504		ps	
011		623		ps	
100		743		ps	
101		866		ps	
110		989		ps	
111		1112		ps	
PLL R DIVIDER DELAY					Register 0x019[5:3]; see Table 47
000		Off			
001		365		ps	
010		486		ps	
011		608		ps	
100		730		ps	
101		852		ps	
110		976		ps	
111		1101		ps	
PHASE OFFSET IN ZERO DELAY					REF refers to REFIN (REF1)/$\overline{\text{REFIN}}$ (REF2)
Phase Offset (REF-to-LVDS Clock Output Pins) in Zero Delay Mode	1890	2348	3026	ps	When N delay and R delay are bypassed
Phase Offset (REF-to-LVDS Clock Output Pins) in Zero Delay Mode	900	1217	1695	ps	When N delay = Setting 111 and R delay is bypassed

Parameter	Min	Typ	Max	Unit	Test Conditions/Comments
NOISE CHARACTERISTICS					
In-Band Phase Noise of the Charge Pump/ Phase Frequency Detector (In-Band Means Within the LBW of the PLL)					The PLL in-band phase noise floor is estimated by measuring the in-band phase noise at the output of the VCO and subtracting 20 log(N) (where N is the value of the N divider)
At 500 kHz PFD Frequency		−165		dBc/Hz	
At 1 MHz PFD Frequency		−162		dBc/Hz	
At 10 MHz PFD Frequency		−152		dBc/Hz	
At 50 MHz PFD Frequency		−144		dBc/Hz	
PLL Figure of Merit (FOM)		−222		dBc/Hz	Reference slew rate > 0.5 V/ns; FOM + 10 log(f_{PFD}) is an approximation of the PFD/CP in-band phase noise (in the flat region) inside the PLL loop bandwidth; when running closed-loop, the phase noise, as observed at the VCO output, is increased by 20 log(N); PLL figure of merit decreases with decreasing slew rate; see Figure 11
PLL DIGITAL LOCK DETECT WINDOW[2]					Signal available at the LD, STATUS, and REFMON pins when selected by appropriate register settings; lock detect window settings can be varied by changing the CPRSET resistor
Lock Threshold (Coincidence of Edges)					Selected by Register 0x017[1:0] and Register 0x018[4] (this is the threshold to go from unlock to lock)
Low Range (ABP 1.3 ns, 2.9 ns)		3.5		ns	Register 0x017[1:0] = 00b, 01b, 11b; Register 0x018[4] = 1b
High Range (ABP 1.3 ns, 2.9 ns)		7.5		ns	Register 0x017[1:0] = 00b, 01b, 11b; Register 0x018[4] = 0b
High Range (ABP 6.0 ns)		3.5		ns	Register 0x017[1:0] = 10b; Register 0x018[4] = 0b
Unlock Threshold (Hysteresis)[2]					Selected by Register 0x017[1:0] and Register 0x018[4] (this is the threshold to go from lock to unlock)
Low Range (ABP 1.3 ns, 2.9 ns)		7		ns	Register 0x017[1:0] = 00b, 01b, 11b; Register 0x018[4] = 1b
High Range (ABP 1.3 ns, 2.9 ns)		15		ns	Register 0x017[1:0] = 00b, 01b, 11b; Register 0x018[4] = 0b
High Range (ABP 6.0 ns)		11		ns	Register 0x017[1:0] = 10b; Register 0x018[4] = 0b

[1] The REFIN and $\overline{\text{REFIN}}$ self-bias points are offset slightly to avoid chatter on an open input condition.
[2] For reliable operation of the digital lock detect, the period of the PFD frequency must be greater than the unlock-after-lock time.

CLOCK INPUTS

Table 3.

Parameter	Min	Typ	Max	Unit	Test Conditions/Comments
CLOCK INPUTS (CLK, $\overline{CLK}$)					Differential input
Input Frequency	0[1]		2.4	GHz	High frequency distribution (VCO divider)
	0[1]		2	GHz	Distribution only (VCO divider bypassed); this is the frequency range supported by the channel divider, see the Channel Divider Maximum Frequency section
Input Sensitivity, Differential		150		mV p-p	Measured at 2.4 GHz; jitter performance is improved with slew rates > 1 V/ns
Input Level, Differential			2	V p-p	Larger voltage swings can turn on the protection diodes and can degrade jitter performance
Input Common-Mode Voltage, V_{CM}	1.3	1.57	1.8	V	Self-biased; enables ac coupling
Input Common-Mode Range, V_{CMR}	1.3		1.8	V	With 200 mV p-p signal applied; dc-coupled
Input Sensitivity, Single-Ended		150		mV p-p	CLK ac-coupled; $\overline{CLK}$ ac-bypassed to RF ground
Input Resistance	3.9	4.7	5.7	kΩ	Self-biased
Input Capacitance		2		pF	

[1] Below about 1 MHz, the input must be dc-coupled. Take care to match V_{CM}.

CLOCK OUTPUTS

Table 4.

Parameter	Min	Typ	Max	Unit	Test Conditions/Comments
LVDS CLOCK OUTPUTS					Termination = 100 Ω across differential pair
OUT0, OUT1, OUT2, OUT3, OUT4, OUT5, OUT6, OUT7, OUT8, OUT9, OUT10, OUT11					Differential (OUT, $\overline{OUT}$)
Output Frequency			800	MHz	The AD9522 outputs toggle at higher frequencies, but the output amplitude may not meet the V_{OD} specification
Output Differential Voltage, V_{OD}	247	360	454	mV	$V_{OH} - V_{OL}$ for each leg of a differential pair for default amplitude setting with the driver not toggling; the peak-to-peak amplitude measured using a differential probe across the differential pair with the driver toggling is roughly 2× these values (see Figure 17)
Delta V_{OD}			25	mV	Absolute difference between voltage swing of normal pin and inverted pin, output driver static
Output Offset Voltage, V_{OS}	1.125	1.25	1.375	V	$(V_{OH} + V_{OL})/2$ across a differential pair
Delta V_{OS}			25	mV	This is the absolute value of the difference between V_{OS} when the normal output is high vs. when the complementary output is high
Short-Circuit Current, I_{SA}, I_{SB}		14	24	mA	Output shorted to GND
Tristate Leakage Current per Output		<1		nA	Output in tristate with 100 Ω across differential pair
CMOS CLOCK OUTPUTS					
OUT0A, OUT0B, OUT1A, OUT1B, OUT2A, OUT2B, OUT3A, OUT3B, OUT4A, OUT4B, OUT5A, OUT5B, OUT6A, OUT6B, OUT7A, OUT7B, OUT8A, OUT8B, OUT9A, OUT9B, OUT10A, OUT10B, OUT11A, OUT11B					Single-ended; termination = 10 pF
Output Frequency			250	MHz	See Figure 18
Output Voltage High, V_{OH}	VS − 0.1			V	At 1 mA load
Output Voltage Low, V_{OL}			0.1	V	At 1 mA load
Output Voltage High, V_{OH}	2.7			V	At 10 mA load
Output Voltage Low, V_{OL}			0.5	V	At 10 mA load

TIMING CHARACTERISTICS

Table 5.

Parameter	Min	Typ	Max	Unit	Test Conditions/Comments
LVDS OUTPUT RISE/FALL TIMES					Termination = 100 Ω across differential pair
Output Rise Time, t_{RP}		150	350	ps	20% to 80%, measured differentially
Output Fall Time, t_{FP}		150	350	ps	80% to 20%, measured differentially
PROPAGATION DELAY, t_{LVDS}, CLK-TO-LVDS OUTPUT					
For All Divide Values	1866	2313	2812	ps	High frequency clock distribution configuration
	1808	2245	2740	ps	Clock distribution configuration
Variation with Temperature		1		ps/°C	
OUTPUT SKEW, LVDS OUTPUTS[1]					Termination = 100 Ω across differential pair
LVDS Outputs That Share the Same Divider		7	60	ps	
LVDS Outputs on Different Dividers		19	162	ps	
All LVDS Outputs Across Multiple Parts			432	ps	
CMOS OUTPUT RISE/FALL TIMES					Termination = open
Output Rise Time, t_{RC}		625	835	ps	20% to 80%; C_{LOAD} = 10 pF
Output Fall Time, t_{FC}		625	800	ps	80% to 20%; C_{LOAD} = 10 pF
PROPAGATION DELAY, t_{CMOS}, CLK-TO-CMOS OUTPUT					Clock distribution configuration
For All Divide Values	1913	2400	2950	ps	
Variation with Temperature		2		ps/°C	
OUTPUT SKEW, CMOS OUTPUTS[1]					
CMOS Outputs That Share the Same Divider		10	55	ps	
All CMOS Outputs on Different Dividers		27	230	ps	
All CMOS Outputs Across Multiple Parts			500	ps	
OUTPUT SKEW, LVDS-TO-CMOS OUTPUT[1]					All settings identical; different logic type
Outputs That Share the Same Divider	−31	+152	+495	ps	LVDS to CMOS on the same part
Outputs That Are on Different Dividers	−193	+160	+495	ps	LVDS to CMOS on the same part

[1] The output skew is the difference between any two similar delay paths while operating at the same voltage and temperature.

Timing Diagrams

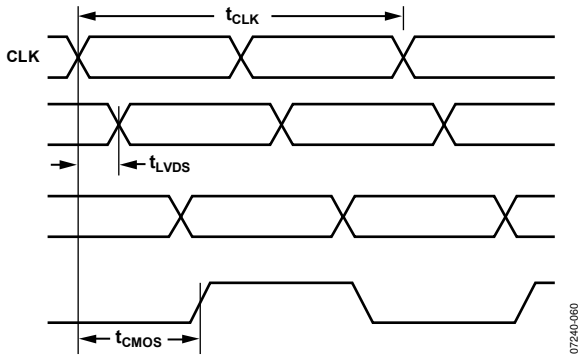

Figure 2. CLK/$\overline{CLK}$ to Clock Output Timing, DIV = 1

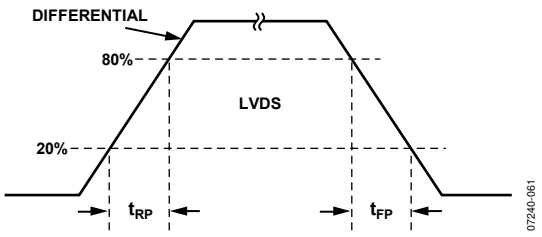

Figure 3. LVDS Timing, Differential

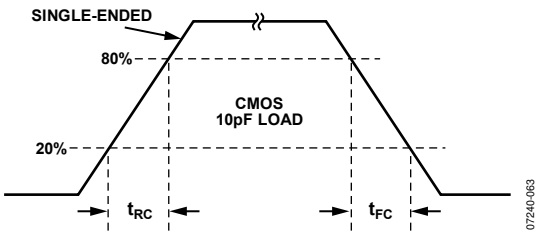

Figure 4. CMOS Timing, Single-Ended, 10 pF Load

CLOCK OUTPUT ADDITIVE PHASE NOISE (DISTRIBUTION ONLY; VCO DIVIDER NOT USED)

Table 6.

Parameter	Min	Typ	Max	Unit	Test Conditions/Comments
CLK-TO-LVDS ADDITIVE PHASE NOISE					Distribution section only; does not include PLL and VCO
CLK = 1.6 GHz, Output = 800 MHz					Input slew rate > 1 V/ns
Divider = 2					
At 10 Hz Offset		−100		dBc/Hz	
At 100 Hz Offset		−110		dBc/Hz	
At 1 kHz Offset		−117		dBc/Hz	
At 10 kHz Offset		−126		dBc/Hz	
At 100 kHz Offset		−134		dBc/Hz	
At 1 MHz Offset		−137		dBc/Hz	
At 10 MHz Offset		−147		dBc/Hz	
At 100 MHz Offset		−148		dBc/Hz	
CLK = 1 GHz, Output = 200 MHz					Input slew rate > 1 V/ns
Divider = 5					
At 10 Hz Offset		−111		dBc/Hz	
At 100 Hz Offset		−123		dBc/Hz	
At 1 kHz Offset		−132		dBc/Hz	
At 10 kHz Offset		−141		dBc/Hz	
At 100 kHz Offset		−146		dBc/Hz	
At 1 MHz Offset		−150		dBc/Hz	
>10 MHz Offset		−156		dBc/Hz	
CLK-TO-CMOS ADDITIVE PHASE NOISE					Distribution section only; does not include PLL and VCO
CLK = 1 GHz, Output = 500 MHz					Input slew rate > 1 V/ns
Divider = 2					
At 10 Hz Offset		−102		dBc/Hz	
At 100 Hz Offset		−114		dBc/Hz	
At 1 kHz Offset		−122		dBc/Hz	
At 10 kHz Offset		−129		dBc/Hz	
At 100 kHz Offset		−135		dBc/Hz	
At 1 MHz Offset		−140		dBc/Hz	
>10 MHz Offset		−150		dBc/Hz	
CLK = 1 GHz, Output = 50 MHz					Input slew rate > 1 V/ns
Divider = 20					
At 10 Hz Offset		−125		dBc/Hz	
At 100 Hz Offset		−136		dBc/Hz	
At 1 kHz Offset		−144		dBc/Hz	
At 10 kHz Offset		−152		dBc/Hz	
At 100 kHz Offset		−157		dBc/Hz	
At 1 MHz Offset		−160		dBc/Hz	
>10 MHz Offset		−164		dBc/Hz	

CLOCK OUTPUT ABSOLUTE TIME JITTER (CLOCK GENERATION USING EXTERNAL VCXO)

Table 7.

Parameter	Min	Typ	Max	Unit	Test Conditions/Comments
LVDS OUTPUT ABSOLUTE TIME JITTER					Application example based on a typical setup using an external 245.76 MHz VCXO (Toyocom TCO-2112); reference = 15.36 MHz; R DIV = 1
LVDS = 245.76 MHz; PLL LBW = 125 Hz		87		fs rms	Integration bandwidth = 200 kHz to 5 MHz
		108		fs rms	Integration bandwidth = 200 kHz to 10 MHz
		146		fs rms	Integration bandwidth = 12 kHz to 20 MHz
LVDS = 122.88 MHz; PLL LBW = 125 Hz		120		fs rms	Integration bandwidth = 200 kHz to 5 MHz
		151		fs rms	Integration bandwidth = 200 kHz to 10 MHz
		207		fs rms	Integration bandwidth = 12 kHz to 20 MHz
LVDS = 61.44 MHz; PLL LBW = 125 Hz		157		fs rms	Integration bandwidth = 200 kHz to 5 MHz
		210		fs rms	Integration bandwidth = 200 kHz to 10 MHz
		295		fs rms	Integration bandwidth = 12 kHz to 20 MHz

CLOCK OUTPUT ADDITIVE TIME JITTER (VCO DIVIDER NOT USED)

Table 8.

Parameter	Min	Typ	Max	Unit	Test Conditions/Comments
LVDS OUTPUT ADDITIVE TIME JITTER					Distribution section only; does not include PLL and VCO; measured at rising edge of clock signal
CLK = 622.08 MHz Any LVDS Output = 622.08 MHz Divide Ratio = 1		69		fs rms	Integration bandwidth = 12 kHz to 20 MHz
CLK = 622.08 MHz Any LVDS Output = 155.52 MHz Divide Ratio = 4		116		fs rms	Integration bandwidth = 12 kHz to 20 MHz
CLK = 100 MHz Any LVDS Output = 100 MHz Divide Ratio = 1		263		fs rms	Calculated from SNR of ADC method Broadband jitter
CLK = 500 MHz Any LVDS Output = 100 MHz Divide Ratio = 5		242		fs rms	Calculated from SNR of ADC method Broadband jitter
CMOS OUTPUT ADDITIVE TIME JITTER					Distribution section only; does not include PLL and VCO
CLK = 200 MHz Any CMOS Output Pair = 100 MHz Divide Ratio = 2		289		fs rms	Calculated from SNR of ADC method Broadband jitter

CLOCK OUTPUT ADDITIVE TIME JITTER (VCO DIVIDER USED)

Table 9.

Parameter	Min	Typ	Max	Unit	Test Conditions/Comments
LVDS OUTPUT ADDITIVE TIME JITTER					Distribution section only; does not include PLL and VCO; uses rising edge of clock signal
CLK = 500 MHz; VCO DIV = 5; LVDS = 100 MHz; Bypass Channel Divider; Duty-Cycle Correction = On		248		fs rms	Calculated from SNR of ADC method (broadband jitter)
CMOS OUTPUT ADDITIVE TIME JITTER					Distribution section only; does not include PLL and VCO; uses rising edge of clock signal
CLK = 200 MHz; VCO DIV = 2; CMOS = 100 MHz; Bypass Channel Divider; Duty-Cycle Correction = Off		290		fs rms	Calculated from SNR of ADC method (broadband jitter)
CLK = 200 MHz; VCO DIV = 1; CMOS = 100 MHz; Bypass Channel Divider; Duty-Cycle Correction = Off		288		fs rms	Calculated from SNR of ADC method (broadband jitter)

SERIAL CONTROL PORT—SPI MODE

Table 10.

Parameter	Min	Typ	Max	Unit	Test Conditions/Comments
$\overline{CS}$ (INPUT)					$\overline{CS}$ has an internal 30 kΩ pull-up resistor
Input Logic 1 Voltage	2.0			V	
Input Logic 0 Voltage			0.8	V	
Input Logic 1 Current			3	μA	
Input Logic 0 Current		−110		μA	The minus sign indicates that current is flowing out of the AD9522, which is due to the internal pull-up resistor
Input Capacitance		2		pF	
SCLK (INPUT) IN SPI MODE					SCLK has an internal 30 kΩ pull-down resistor in SPI mode, but not in I^2C mode
Input Logic 1 Voltage	2.0			V	
Input Logic 0 Voltage			0.8	V	
Input Logic 1 Current		110		μA	
Input Logic 0 Current			1	μA	
Input Capacitance		2		pF	
SDIO (WHEN AN INPUT IN BIDIRECTIONAL MODE)					
Input Logic 1 Voltage	2.0			V	
Input Logic 0 Voltage			0.8	V	
Input Logic 1 Current		1		μA	
Input Logic 0 Current		1		μA	
Input Capacitance		2		pF	
SDIO, SDO (OUTPUTS)					
Output Logic 1 Voltage	2.7			V	At 1 mA current; maximum recommended current: 5 mA
Output Logic 0 Voltage			0.4	V	At 1 mA current
TIMING					
Clock Rate (SCLK, $1/t_{SCLK}$)			25	MHz	
Pulse Width High, t_{HIGH}	16			ns	
Pulse Width Low, t_{LOW}	16			ns	
SDIO to SCLK Setup, t_{DS}	4			ns	
SCLK to SDIO Hold, t_{DH}	0			ns	
SCLK to Valid SDIO and SDO, t_{DV}			11	ns	
$\overline{CS}$ to SCLK Setup and Hold, t_S, t_C	2			ns	
$\overline{CS}$ Minimum Pulse Width High, t_{PWH}	3			ns	

SERIAL CONTROL PORT—I²C MODE

Table 11.

Parameter	Min	Typ	Max	Unit	Test Conditions/Comments
SDA, SCL (WHEN INPUTTING DATA)					
Input Logic 1 Voltage	0.7 × VS			V	
Input Logic 0 Voltage			0.3 × VS	V	
Input Current with an Input Voltage Between 0.1 × VS and 0.9 × VS	−10		+10	µA	
Hysteresis of Schmitt Trigger Inputs	0.015 × VS			V	
Pulse Width of Spikes That Must Be Suppressed by the Input Filter, t_{SPIKE}			50	ns	
SDA (WHEN OUTPUTTING DATA)					
Output Logic 0 Voltage at 3 mA Sink Current			0.4	V	
Output Fall Time from VIH_{MIN} to VIL_{MAX} with a Bus Capacitance from 10 pF to 400 pF	20 + 0.1 C_b		250	ns	C_b = capacitance of one bus line in pF
TIMING					Note that all I²C timing values refer to VIH_{MIN} (0.3 × VS) and VIL_{MAX} levels (0.7 × VS)
Clock Rate (SCL, f_{I2C})			400	kHz	
Bus Free Time Between a Stop and Start Condition, t_{IDLE}	1.3			µs	
Setup Time for a Repeated Start Condition, $t_{SET; STR}$	0.6			µs	
Hold Time (Repeated) Start Condition (After This Period, the First Clock Pulse Is Generated), $t_{HLD; STR}$	0.6			µs	
Setup Time for Stop Condition, $t_{SET; STP}$	0.6			µs	
Low Period of the SCL Clock, t_{LOW}	1.3			µs	
High Period of the SCL Clock, t_{HIGH}	0.6			µs	
SCL, SDA Rise Time, t_{RISE}	20 + 0.1 C_b		300	ns	C_b = capacitance of one bus line in pF
SCL, SDA Fall Time, t_{FALL}	20 + 0.1 C_b		300	ns	C_b = capacitance of one bus line in pF
Data Setup Time, $t_{SET; DAT}$	120			ns	This is a minor deviation from the original I²C specification of 100 ns minimum
Data Hold Time, $t_{HLD; DAT}$	140		880	ns	This is a minor deviation from the original I²C specification of 0 ns minimum[1]
Capacitive Load for Each Bus Line, C_b			400	pF	

[1] According to the original I²C specification, an I²C master must also provide a minimum hold time of 300 ns for the SDA signal to bridge the undefined region of the SCL falling edge.

$\overline{PD}$, $\overline{SYNC}$, AND $\overline{RESET}$ PINS

Table 12.

Parameter	Min	Typ	Max	Unit	Test Conditions/Comments
INPUT CHARACTERISTICS					Each of these pins has an 30 kΩ internal pull-up resistor
Logic 1 Voltage	2.0			V	
Logic 0 Voltage			0.8	V	
Logic 1 Current			1	µA	
Logic 0 Current		−110		µA	The minus sign indicates that current is flowing out of the AD9522, which is due to the internal pull-up resistor
Capacitance		2		pF	
RESET TIMING					
Pulse Width Low	50			ns	
$\overline{RESET}$ Inactive to Start of Register Programming	100			ns	
$\overline{SYNC}$ TIMING					
Pulse Width Low	1.3			ns	High speed clock is CLK input signal

SERIAL PORT SETUP PINS: SP1, SP0

Table 13.

Parameter	Min	Typ	Max	Unit	Test Conditions/Comments
SP1, SP0					These pins do not have internal pull-up/pull-down resistors
Logic Level 0			0.25 × VS	V	VS is the voltage on the VS pin
Logic Level ½	0.4 × VS		0.65 × VS	V	User can float these pins to obtain Logic Level ½; if floating this pin, connect a capacitor to ground
Logic Level 1	0.8 × VS			V	

LD, STATUS, AND REFMON PINS

Table 14.

Parameter	Min	Typ	Max	Unit	Test Conditions/Comments
OUTPUT CHARACTERISTICS					When selected as a digital output (CMOS); there are other modes in which these pins are not CMOS digital outputs; see Table 47, Register 0x017, Register 0x01A, and Register 0x01B
Output Voltage High, V_{OH}	2.7			V	At 1 mA current; maximum recommended current: 5 mA
Output Voltage Low, V_{OL}			0.4	V	At 1 mA current
MAXIMUM TOGGLE RATE		100		MHz	Applies when mux is set to any divider or counter output, or PFD up/down pulse; also applies in analog lock detect mode; usually debug mode only; note that spurs can couple to output when any of these pins are toggling
ANALOG LOCK DETECT					
Capacitance		3		pF	On-chip capacitance; used to calculate RC time constant for analog lock detect read back; use a pull-up resistor
REF1, REF2, AND CLK FREQUENCY STATUS MONITOR					
Normal Range	1.02			MHz	Frequency above which the monitor indicates the presence of the reference
Extended Range	8			kHz	Frequency above which the monitor indicates the presence of the reference
LD PIN COMPARATOR					
Trip Point		1.6		V	
Hysteresis		260		mV	

POWER DISSIPATION

Table 15.

Parameter	Min	Typ	Max	Unit	Test Conditions/Comments
POWER DISSIPATION, CHIP					Does not include power dissipated in external resistors; all LVDS outputs terminated with 100 Ω across differential pair; all CMOS outputs have 10 pF capacitive loading
Power-On Default		0.88	1.0	W	No clock; no programming; default register values
Distribution Only Mode; VCO Divider On; One LVDS Output Enabled		0.36	0.43	W	f_{CLK} = 2.4 GHz; f_{OUT} = 200 MHz; VCO divider = 2; one LVDS output and output divider enabled; zero delay off
Distribution Only Mode; VCO Divider Off; One LVDS Output Enabled		0.33	0.4	W	f_{CLK} = 2.4 GHz; f_{OUT} = 200 MHz; VCO divider bypassed; one LVDS output and output divider enabled; zero delay off
Maximum Power, Full Operation		1.1	1.3	W	PLL on; VCO divider = 3; all channel dividers on; 12 LVDS outputs at 125 MHz; zero delay on
$\overline{PD}$ Power-Down		35	50	mW	$\overline{PD}$ pin pulled low; does not include power dissipated in termination resistors
$\overline{PD}$ Power-Down, Maximum Sleep		27	43	mW	$\overline{PD}$ pin pulled low; PLL power-down, Register 0x010[1:0] = 01b; power-down SYNC, Register 0x230[2] = 1b; power-down distribution reference, Register 0x230[1] = 1b
VCP Supply		2.3	8	mW	PLL operating; typical closed-loop configuration
POWER DELTAS, INDIVIDUAL FUNCTIONS					Power delta when a function is enabled/disabled
VCO Divider On/Off		33	43	mW	VCO divider not used
REFIN (Differential) Off		25	31	mW	Delta between reference input off and differential reference input mode
REF1, REF2 (Single-Ended) On/Off		16	22	mW	Delta between reference inputs off and one single-ended reference enabled; double this number if both REF1 and REF2 are powered up
PLL Dividers and Phase Detector On/Off		54	67	mW	PLL off to PLL on, normal operation; no reference enabled
LVDS Channel		118	146	mW	No LVDS output on to one LVDS output on; channel divider set to 1
LVDS Driver		11	15	mW	Second LVDS output turned on, same channel
CMOS Channel		120	154	mW	No CMOS output on to one CMOS output on; channel divider set to 1; f_{OUT} = 62.5 MHz and 10 pF of capacitive loading
CMOS Driver On/Off		16	30	mW	Additional CMOS outputs within the same channel turned on
Channel Divider Enabled		33	40	mW	Delta between divider bypassed (divide-by-1) and divide-by-2 to divide-by-32
Zero Delay Block On/Off		30	35	mW	

ABSOLUTE MAXIMUM RATINGS

Table 16.

Parameter or Pin	With Respect to	Rating
VS	GND	−0.3 V to +3.6 V
VCP, CP	GND	−0.3 V to +5.8 V
REFIN, $\overline{\text{REFIN}}$	GND	−0.3 V to VS + 0.3 V
RSET	GND	−0.3 V to VS + 0.3 V
CPRSET	GND	−0.3 V to VS + 0.3 V
CLK, $\overline{\text{CLK}}$	GND	−0.3 V to VS + 0.3 V
CLK	$\overline{\text{CLK}}$	−1.2 V to +1.2 V
SCLK/SCL, SDIO/SDA, SDO, $\overline{\text{CS}}$	GND	−0.3 V to VS + 0.3 V
OUT0, $\overline{\text{OUT0}}$, OUT1, $\overline{\text{OUT1}}$, OUT2, $\overline{\text{OUT2}}$, OUT3, $\overline{\text{OUT3}}$, OUT4, $\overline{\text{OUT4}}$, OUT5, $\overline{\text{OUT5}}$, OUT6, $\overline{\text{OUT6}}$, OUT7, $\overline{\text{OUT7}}$, OUT8, $\overline{\text{OUT8}}$, OUT9, $\overline{\text{OUT9}}$, OUT10, $\overline{\text{OUT10}}$, OUT11, $\overline{\text{OUT11}}$	GND	−0.3 V to VS + 0.3 V
$\overline{\text{SYNC}}$, $\overline{\text{RESET}}$, $\overline{\text{PD}}$	GND	−0.3 V to VS + 0.3 V
REFMON, STATUS, LD	GND	−0.3 V to VS + 0.3 V
SP0, SP1, EEPROM	GND	−0.3 V to VS + 0.3 V
Junction Temperature[1]		125°C
Storage Temperature Range		−65°C to +150°C
Lead Temperature (10 sec)		300°C

[1] See the Specifications section for operating temperature range (T_A).

Stresses at or above those listed under Absolute Maximum Ratings may cause permanent damage to the product. This is a stress rating only; functional operation of the product at these or any other conditions above those indicated in the operational section of this specification is not implied. Operation beyond the maximum operating conditions for extended periods may affect product reliability.

THERMAL RESISTANCE

Thermal impedance measurements were taken on a JEDEC JESD51-5 2S2P test board in still air in accordance with JEDEC JESD51-2. See the Thermal Performance section for more details.

Table 17.

Package Type	θ_{JA}	Unit
64-Lead LFCSP (CP-64-4)	22	°C/W

ESD CAUTION

ESD (electrostatic discharge) sensitive device. Charged devices and circuit boards can discharge without detection. Although this product features patented or proprietary protection circuitry, damage may occur on devices subjected to high energy ESD. Therefore, proper ESD precautions should be taken to avoid performance degradation or loss of functionality.

PIN CONFIGURATION AND FUNCTION DESCRIPTIONS

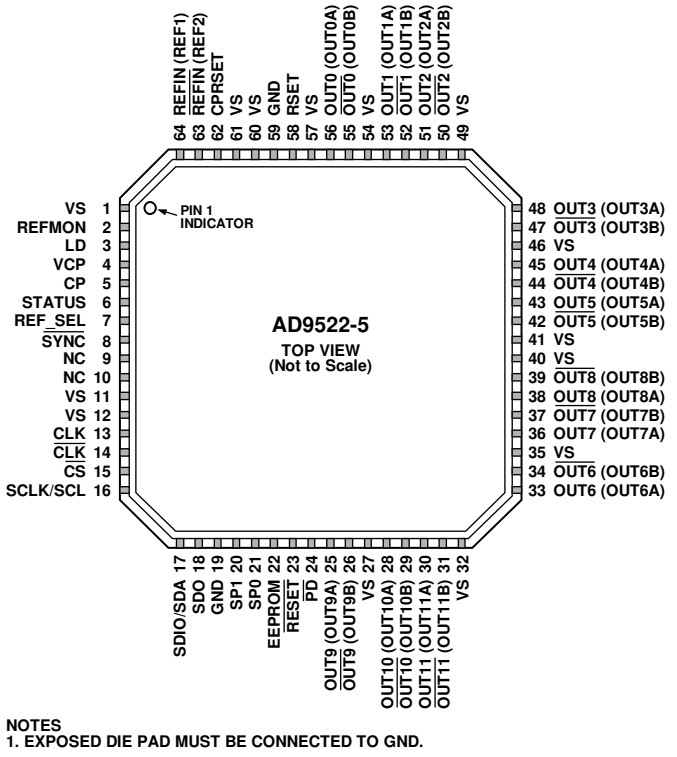

Figure 5. Pin Configuration

Table 18. Pin Function Descriptions

Pin No.	Input/ Output	Pin Type	Mnemonic	Description
1, 11, 12, 27, 32, 35, 40, 41, 46, 49, 54, 57, 60, 61	I	Power	VS	3.3 V Power Pins.
2	O	3.3 V CMOS	REFMON	Reference Monitor (Output). This pin has multiple selectable outputs.
3	O	3.3 V CMOS	LD	Lock Detect (Output). This pin has multiple selectable outputs.
4	I	Power	VCP	Power Supply for Charge Pump (CP); VS ≤ VCP ≤ 5.25 V. VCP must still be connected to 3.3 V if the PLL is not used.
5	O	Loop filter	CP	Charge Pump (Output). This pin connects to an external loop filter. This pin can be left unconnected if the PLL is not used.
6	O	3.3 V CMOS	STATUS	Programmable Status Output.
7	I	3.3 V CMOS	REF_SEL	Reference Select. It selects REF1 (low) or REF2 (high). This pin has an internal 30 kΩ pull-down resistor.
8	I	3.3 V CMOS	$\overline{\text{SYNC}}$	Manual Synchronizations and Manual Holdover. This pin initiates a manual synchronization and is used for manual holdover. Active low. This pin has an internal 30 kΩ pull-up resistor.
9, 10			NC	No Connect. These pins can be left floating.
13	I	Differential clock input	CLK	Along with $\overline{\text{CLK}}$, this pin is the differential input for the clock distribution section.
14	I	Differential clock input	$\overline{\text{CLK}}$	Along with CLK, this pin is the differential input for the clock distribution section. If a single-ended input is connected to the CLK pin, connect a 0.1 µF bypass capacitor from this pin to ground.

Pin No.	Input/ Output	Pin Type	Mnemonic	Description
15	I	3.3 V CMOS	$\overline{CS}$	Serial Control Port Chip Select; Active Low. This pin has an internal 30 kΩ pull-up resistor.
16	I	3.3 V CMOS	SCLK/SCL	Serial Control Port Clock Signal. This pin has an internal 30 kΩ pull-down resistor in SPI mode but is high impedance in I^2C mode.
17	I/O	3.3 V CMOS	SDIO/SDA	Serial Control Port Bidirectional Serial Data In/Out.
18	O	3.3 V CMOS	SDO	Serial Control Port Unidirectional Serial Data Out.
19, 59	I	GND	GND	Ground Pins.
20	I	Three-level logic	SP1	Select SPI or I^2C as the serial interface port and select the I^2C slave address in I^2C mode. Three-level logic. This pin is internally biased for the open logic level.
21	I	Three-level logic	SP0	Select SPI or I^2C as the serial interface port and select the I^2C slave address in I^2C mode. Three-level logic. This pin is internally biased for the open logic level.
22	I	3.3 V CMOS	EEPROM	Setting this pin high selects the register values stored in the internal EEPROM to load at reset and/or power-up. Setting this pin low causes the AD9522 to load the hard-coded default register values at power-up/reset. This pin has an internal 30 kΩ pull-down resistor. Note that to guarantee the proper loading of the EEPROM during startup, a high-low-high pulse on the $\overline{RESET}$ pin occurs after the power supply stabilizes.
23	I	3.3 V CMOS	$\overline{RESET}$	Chip Reset, Active Low. This pin has an internal 30 kΩ pull-up resistor.
24	I	3.3 V CMOS	$\overline{PD}$	Chip Power-Down, Active Low. This pin has an internal 30 kΩ pull-up resistor.
25	O	LVDS or CMOS	OUT9 (OUT9A)	Clock Output. This pin can be configured as one side of a differential LVDS output or as a single-ended CMOS output.
26	O	LVDS or CMOS	$\overline{OUT9}$ (OUT9B)	Clock Output. This pin can be configured as one side of a differential LVDS output or as a single-ended CMOS output.
28	O	LVDS or CMOS	OUT10 (OUT10A)	Clock Output. This pin can be configured as one side of a differential LVDS output or as a single-ended CMOS output.
29	O	LVDS or CMOS	$\overline{OUT10}$ (OUT10B)	Clock Output. This pin can be configured as one side of a differential LVDS output or as a single-ended CMOS output.
30	O	LVDS or CMOS	OUT11 (OUT11A)	Clock Output. This pin can be configured as one side of a differential LVDS output or as a single-ended CMOS output.
31	O	LVDS or CMOS	$\overline{OUT11}$ (OUT11B)	Clock Output. This pin can be configured as one side of a differential LVDS output or as a single-ended CMOS output.
33	O	LVDS or CMOS	OUT6 (OUT6A)	Clock Output. This pin can be configured as one side of a differential LVDS output or as a single-ended CMOS output.
34	O	LVDS or CMOS	$\overline{OUT6}$ (OUT6B)	Clock Output. This pin can be configured as one side of a differential LVDS output or as a single-ended CMOS output.
36	O	LVDS or CMOS	OUT7 (OUT7A)	Clock Output. This pin can be configured as one side of a differential LVDS output or as a single-ended CMOS output.
37	O	LVDS or CMOS	$\overline{OUT7}$ (OUT7B)	Clock Output. This pin can be configured as one side of a differential LVDS output or as a single-ended CMOS output.
38	O	LVDS or CMOS	OUT8 (OUT8A)	Clock Output. This pin can be configured as one side of a differential LVDS output or as a single-ended CMOS output.
39	O	LVDS or CMOS	$\overline{OUT8}$ (OUT8B)	Clock Output. This pin can be configured as one side of a differential LVDS output or as a single-ended CMOS output.
42	O	LVDS or CMOS	$\overline{OUT5}$ (OUT5B)	Clock Output. This pin can be configured as one side of a differential LVDS output or as a single-ended CMOS output.
43	O	LVDS or CMOS	OUT5 (OUT5A)	Clock Output. This pin can be configured as one side of a differential LVDS output or as a single-ended CMOS output.
44	O	LVDS or CMOS	$\overline{OUT4}$ (OUT4B)	Clock Output. This pin can be configured as one side of a differential LVDS output or as a single-ended CMOS output.
45	O	LVDS or CMOS	OUT4 (OUT4A)	Clock Output. This pin can be configured as one side of a differential LVDS output or as a single-ended CMOS output.

Pin No.	Input/ Output	Pin Type	Mnemonic	Description
47	O	LVDS or CMOS	$\overline{\text{OUT3}}$ (OUT3B)	Clock Output. This pin can be configured as one side of a differential LVDS output or as a single-ended CMOS output.
48	O	LVDS or CMOS	OUT3 (OUT3A)	Clock Output. This pin can be configured as one side of a differential LVDS output or as a single-ended CMOS output.
50	O	LVDS or CMOS	$\overline{\text{OUT2}}$ (OUT2B)	Clock Output. This pin can be configured as one side of a differential LVDS output or as a single-ended CMOS output.
51	O	LVDS or CMOS	OUT2 (OUT2A)	Clock Output. This pin can be configured as one side of a differential LVDS output or as a single-ended CMOS output.
52	O	LVDS or CMOS	$\overline{\text{OUT1}}$ (OUT1B)	Clock Output. This pin can be configured as one side of a differential LVDS output or as a single-ended CMOS output.
53	O	LVDS or CMOS	OUT1 (OUT1A)	Clock Output. This pin can be configured as one side of a differential LVDS output or as a single-ended CMOS output.
55	O	LVDS or CMOS	$\overline{\text{OUT0}}$ (OUT0B)	Clock Output. This pin can be configured as one side of a differential LVDS output or as a single-ended CMOS output.
56	O	LVDS or CMOS	OUT0 (OUT0A)	Clock Output. This pin can be configured as one side of a differential LVDS output or as a single-ended CMOS output.
58	O	Current set resistor	RSET	Clock Distribution Current Set Resistor. Connect a 4.12 kΩ resistor from this pin to GND.
62	O	Current set resistor	CPRSET	Charge Pump Current Set Resistor. Connect a 5.1 kΩ resistor from this pin to GND. This resistor can be omitted if the PLL is not used.
63	I	Reference input	$\overline{\text{REFIN}}$ (REF2)	Along with REFIN, this is the differential input for the PLL reference. Alternatively, this pin is a single-ended input for REF2.
64	I	Reference input	REFIN (REF1)	Along with $\overline{\text{REFIN}}$, this is the differential input for the PLL reference. Alternatively, this pin is a single-ended input for REF1.
EPAD		GND	GND	The exposed die pad must be connected to GND.

TYPICAL PERFORMANCE CHARACTERISTICS

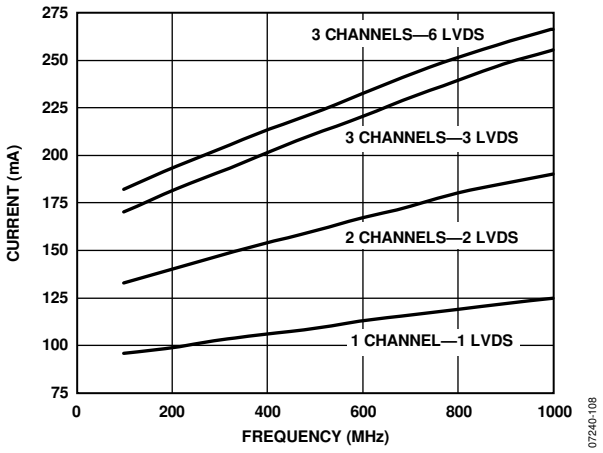

Figure 6. Total Current vs. Frequency, CLK-to-Output (PLL Off), Channel and VCO Divider Bypassed, LVDS Outputs Terminated 100 Ω Across Differential Pair

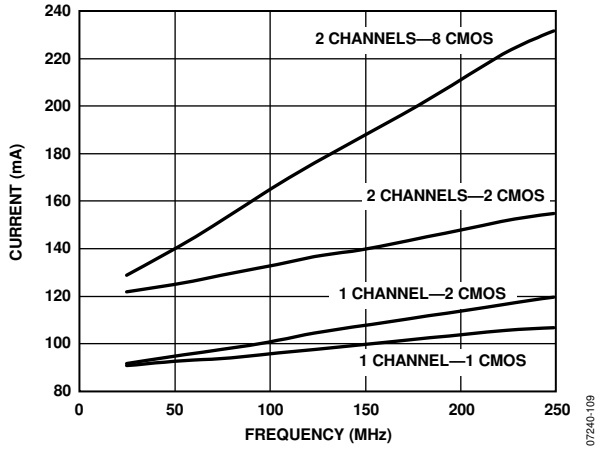

Figure 7. Total Current vs. Frequency, CLK-to-Output (PLL Off), Channel and VCO Divider Bypassed, CMOS Outputs with 10 pF Load

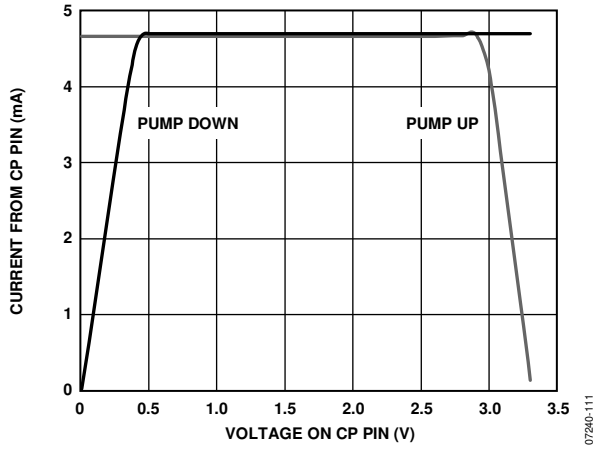

Figure 8. Charge Pump Characteristics at VCP = 3.3 V

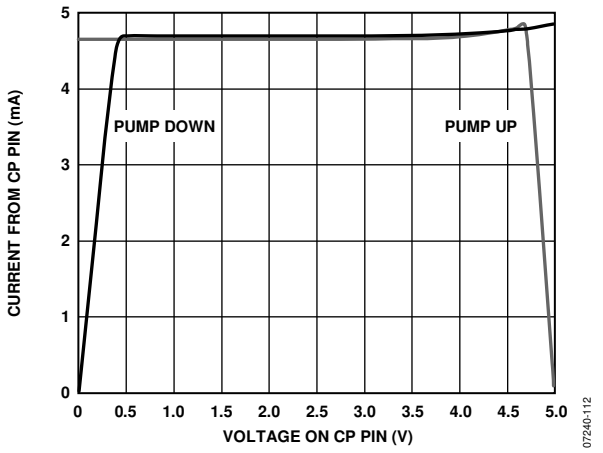

Figure 9. Charge Pump Characteristics at VCP = 5.0 V

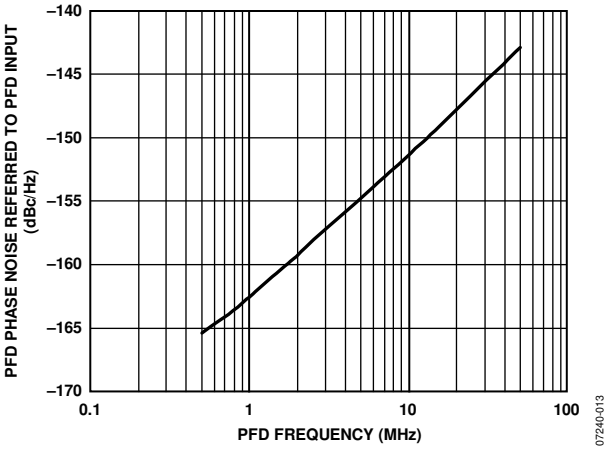

Figure 10. PFD Phase Noise Referred to PFD Input vs. PFD Frequency

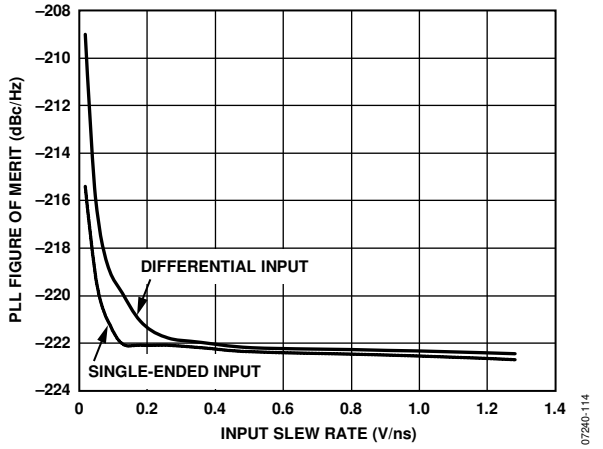

Figure 11. PLL Figure of Merit (FOM) vs. Slew Rate at REFIN/$\overline{\text{REFIN}}$

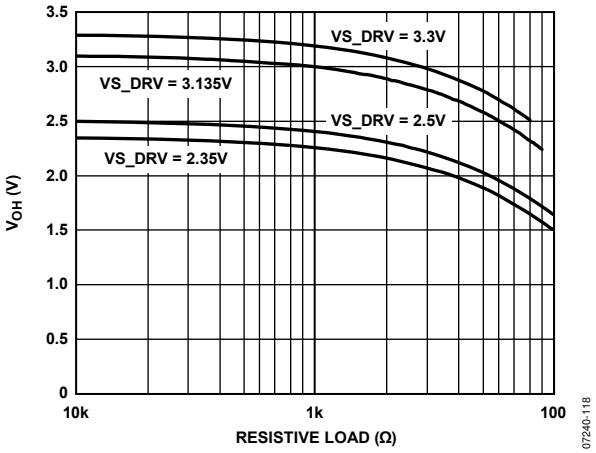

Figure 12. CMOS Output V_{OH} (Static) vs. R_{LOAD} (to Ground)

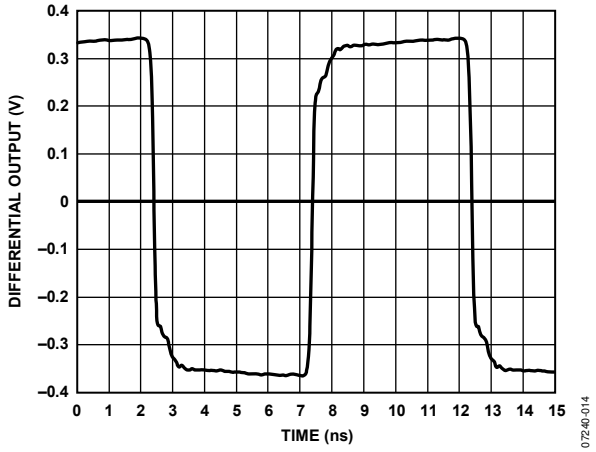

Figure 13. LVDS Output (Differential) at 100 MHz, Output Terminated 100 Ω Across Differential Pair

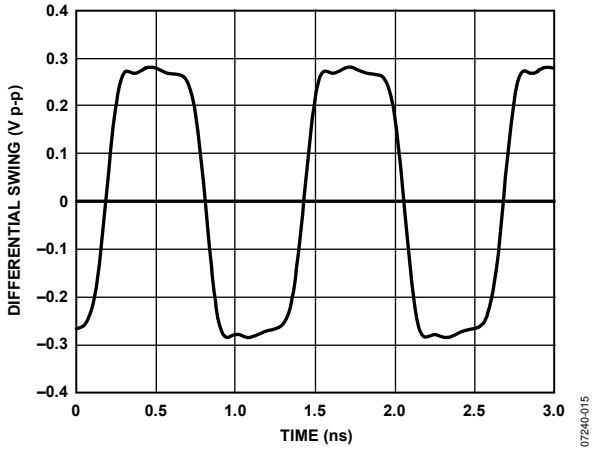

Figure 14. LVDS Differential Voltage Swing at 800 MHz, Output Terminated 100 Ω Across Differential Pair

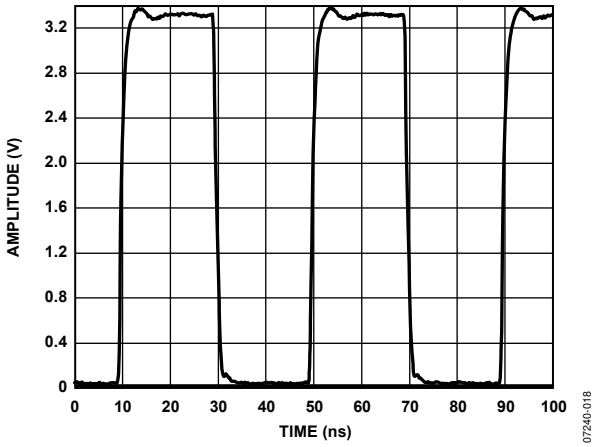

Figure 15. CMOS Output with 10 pF Load at 25 MHz

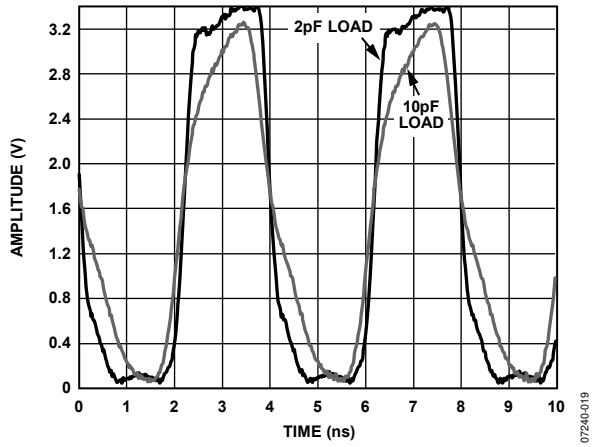

Figure 16. CMOS Output with 2 pF and 10 pF Load at 250 MHz

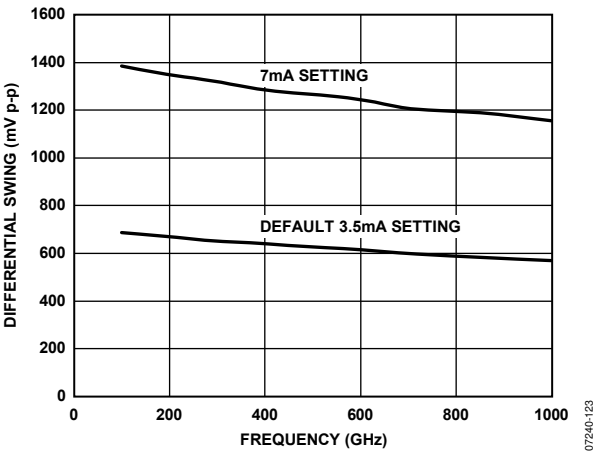

Figure 17. LVDS Differential Voltage Swing vs. Frequency, Output Terminated 100 Ω Across Differential Pair

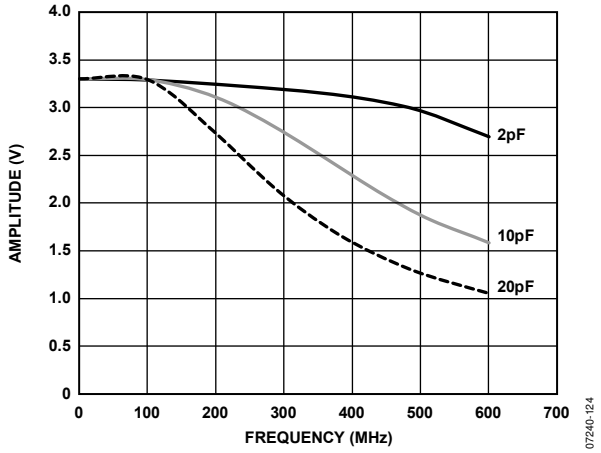

Figure 18. CMOS Output Swing vs. Frequency and Capacitive Load

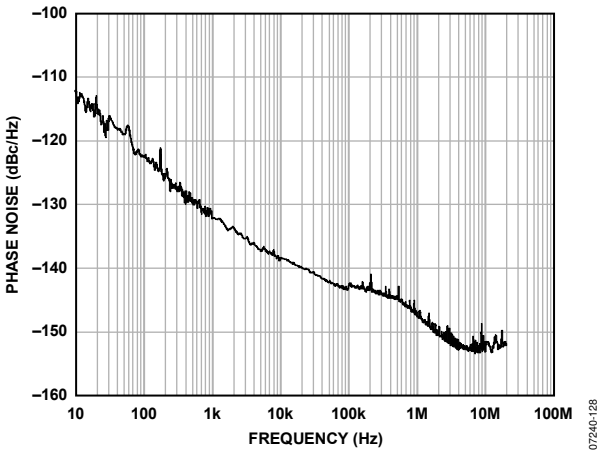

Figure 19. Additive (Residual) Phase Noise, CLK-to-LVDS at 245.76 MHz, Divide-by-1

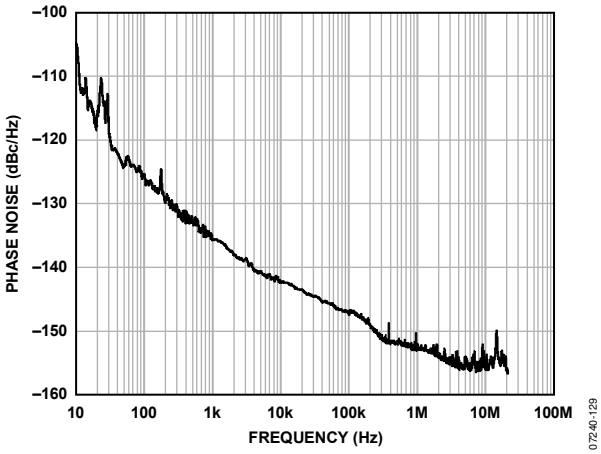

Figure 20. Additive (Residual) Phase Noise, CLK-to-LVDS at 200 MHz, Divide-by-5

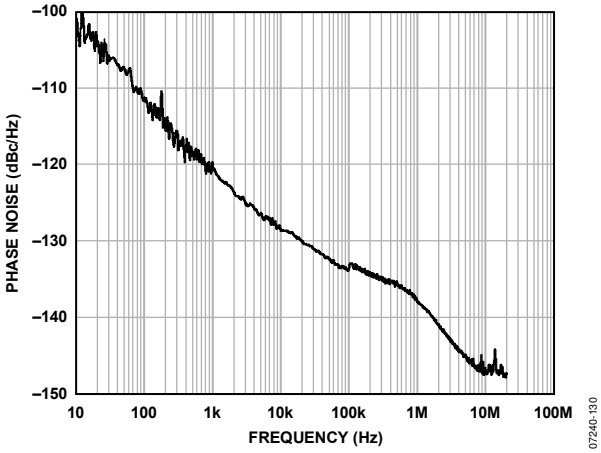

Figure 21. Additive (Residual) Phase Noise, CLK-to-LVDS at 800 MHz, Divide-by-1

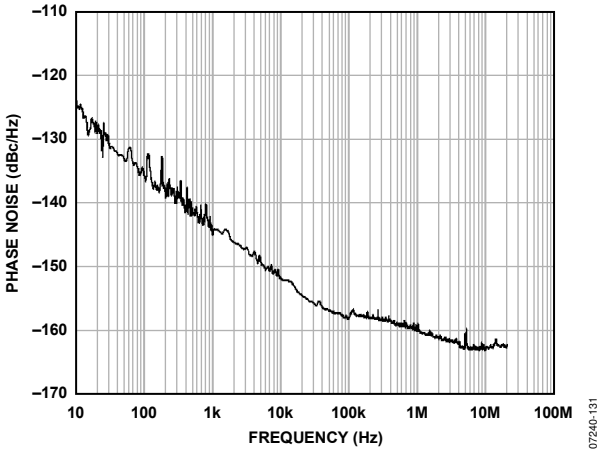

Figure 22. Additive (Residual) Phase Noise, CLK-to-CMOS at 50 MHz, Divide-by-20

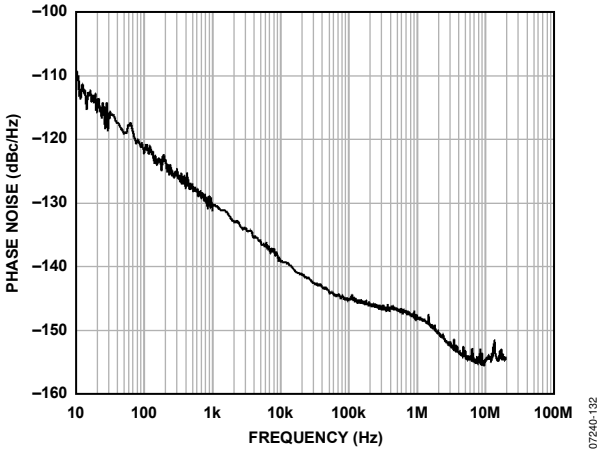

Figure 23. Additive (Residual) Phase Noise, CLK-to-CMOS at 250 MHz, Divide-by-4

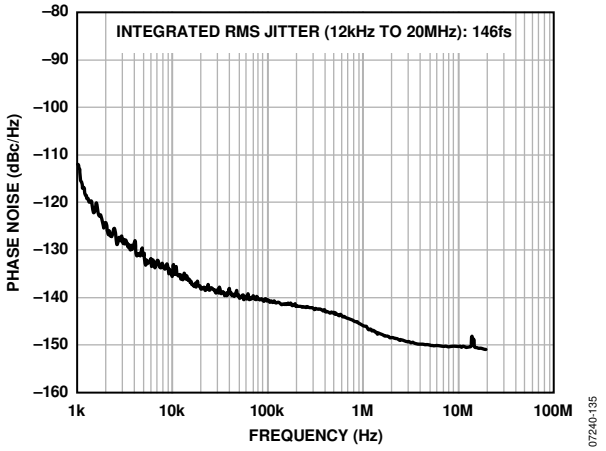

Figure 24. Phase Noise (Absolute), External VCXO (Toyocom TCO-2112) at 245.76 MHz; PFD = 15.36 MHz; LBW = 250 Hz; LVDS Output = 245.76 MHz

TERMINOLOGY

Phase Jitter and Phase Noise
An ideal sine wave can be thought of as having a continuous and even progression of phase with time from 0° to 360° for each cycle. Actual signals, however, display a certain amount of variation from ideal phase progression over time. This phenomenon is called phase jitter. Although many causes can contribute to phase jitter, one major cause is random noise, which is characterized statistically as Gaussian (normal) in distribution.

This phase jitter leads to a spreading out of the energy of the sine wave in the frequency domain, producing a continuous power spectrum. This power spectrum is usually reported as a series of values whose units are dBc/Hz at a given offset in frequency from the sine wave (carrier). The value is a ratio (expressed in decibels) of the power contained within a 1 Hz bandwidth with respect to the power at the carrier frequency. For each measurement, the offset from the carrier frequency is also given.

It is meaningful to integrate the total power contained within some interval of offset frequencies (for example, 10 kHz to 10 MHz). This is called the integrated phase noise over that frequency offset interval and can be readily related to the time jitter due to the phase noise within that offset frequency interval.

Phase noise has a detrimental effect on the performance of ADCs, DACs, and RF mixers. It lowers the achievable dynamic range of the converters and mixers, although they are affected in somewhat different ways.

Time Jitter
Phase noise is a frequency domain phenomenon. In the time domain, the same effect is exhibited as time jitter. When observing a sine wave, the time of successive zero crossings varies. In a square wave, the time jitter is a displacement of the edges from their ideal (regular) times of occurrence. In both cases, the variations in timing from the ideal are the time jitter. Because these variations are random in nature, the time jitter is specified in seconds root mean square (rms) or 1 sigma of the Gaussian distribution.

Time jitter that occurs on a sampling clock for a DAC or an ADC decreases the signal-to-noise ratio (SNR) and dynamic range of the converter. A sampling clock with the lowest possible jitter provides the highest performance from a given converter.

Additive Phase Noise
Additive phase noise is the amount of phase noise that is attributable to the device or subsystem being measured. The phase noise of any external oscillators or clock sources is subtracted. This makes it possible to predict the degree to which the device impacts the total system phase noise when used in conjunction with the various oscillators and clock sources, each of which contributes its own phase noise to the total. In many cases, the phase noise of one element dominates the system phase noise. When there are multiple contributors to phase noise, the total is the square root of the sum of squares of the individual contributors.

Additive Time Jitter
Additive time jitter is the amount of time jitter that is attributable to the device or subsystem being measured. The time jitter of any external oscillators or clock sources is subtracted. This makes it possible to predict the degree to which the device impacts the total system time jitter when used in conjunction with the various oscillators and clock sources, each of which contributes its own time jitter to the total. In many cases, the time jitter of the external oscillators and clock sources dominates the system time jitter.